

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	3030	((semiconductor chip circuit electronic) near3 (sort\$3 separat\$3 process\$3 test\$3)) same ((test result parameter variable data flag) near3 reliability)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/06/12 09:44
L2	14818	((209/571) or (209/573) or (324/158.1) or (324/759) or (324/764) or (324/765) or (700/96) or (700/108) or (700/109) or (700/121)). CCLS.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/06/12 09:44
L3	93	((semiconductor chip circuit electronic) near3 (sort\$3 separat\$3 process\$3 test\$3)) same ((parameter variable flag) near3 reliability)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/06/12 09:45
L4	24	l2 and l3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/06/12 09:45
L8	91	("4027246" "4150331" "4166574" "4419747").PN. OR ("4510673").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2008/06/12 09:51
L19	14	("4488354" "4560583").PN. OR ("4953277").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2008/06/12 09:57
S1	515	"209/573" "209.574"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/09/07 13:21
S2	7	"6350959"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2003/09/03 18:05
S3	4	"6373011"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2003/09/03 18:06
S4	55	"5927512"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2003/09/03 18:06
S5	0	"6373011".URPN.	USPAT	OR	ON	2003/09/03 18:15
S6	12135	"209/571" "209/573" "324/158.1" "324/759" "324/764" "324/765" "700/96" "700/108" "700/109" "700/121"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2003/09/05 14:46

S7	6216	((chip circuit electronic) near3 test\$3) same ((stor\$3 sav\$3) and (test result) and (flag data))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2003/09/04 17:06
S8	575	("209/571" "209/573" "324/158.1" "324/759" "324/764" "324/765" "700/96" "700/108" "700/109" "700/121") and (((chip circuit electronic) near3 test\$3) same ((stor\$3 sav\$3) and (test result) and (flag data)))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2003/09/04 17:06
S9	45	((chip circuit electronic) near3 test\$3) same ((stor\$3 sav\$3) and (test result) and (flag data) and (identification near3 code))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/09/06 14:44
S10	20	("209/571" "209/573" "324/158.1" "324/759" "324/764" "324/765" "700/96" "700/108" "700/109" "700/121") and (((chip circuit electronic) near3 test\$3) same ((stor\$3 sav\$3) and (test result) and (flag data) and (identification near3 code)))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2003/09/05 14:46
S11	12135	"209/571" "209/573" "324/158.1" "324/759" "324/764" "324/765" "700/96" "700/108" "700/109" "700/121"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2003/09/05 14:46
S12	45	((chip circuit electronic) near3 test\$3) same ((stor\$3 sav\$3) and (test result) and (flag data) and (identification near3 code))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2003/09/05 14:47
S13	59	((chip circuit electronic) near3 test\$3) same ((stor\$3 sav\$3) and (test result) and (identification near3 code)))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2003/09/05 14:50
S14	20	("209/571" "209/573" "324/158.1" "324/759" "324/764" "324/765" "700/96" "700/108" "700/109" "700/121") and (((chip circuit electronic) near3 test\$3) same ((stor\$3 sav\$3) and (test result) and (flag data) and (identification near3 code)))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/02/23 18:00
S15	3	("5742173" "5805472" "6097204").PN.	USPAT	OR	ON	2003/09/05 14:51

S16	12	("4869636" "5148100" "5184068" "5227717" "5290134" "5307011" "5313156" "5347463" "5625287" "5635832" "5652523" "5654204").PN.	USPAT	OR	ON	2003/09/05 14:52
S17	39	(((((chip circuit electronic) near3 test\$3) same ((stor\$3 sav\$3) and (test result) and (identification near3 code)))) not (("209/571" "209/573" "324/158.1" "324/759" "324/764" "324/765" "700/96" "700/108" "700/109" "700/121") and (((chip circuit electronic) near3 test\$3) same ((stor\$3 sav\$3) and (test result) and (flag data) and (identification near3 code))))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/28 16:18
S18	82	"5301143"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2003/09/05 15:47
S19	60	"5301143".URPN.	USPAT	OR	ON	2003/09/05 15:53
S20	12989	"209/571" "209/573" "324/158.1" "324/759" "324/764" "324/765" "700/96" "700/108" "700/109" "700/121"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/02/23 18:00
S21	9686	((209/571) or (209/573) or (324/158.1) or (324/759) or (324/764) or (324/765) or (700/96) or (700/108) or (700/109) or (700/121)). CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/05 09:48
S22	2	("5505389").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/02/24 13:48
S23	2	("5907492").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/09/07 13:38
S24	20	("4958373" "4967381" "5103166" "5105362" "5217834" "5219765" "5226118" "5271796" "5289113" "5294812" "5301143" "5420796" "5440493" "5442561" "5450326" "5467304" "5483175" "5495417" "5511005" "5568408").PN.	USPAT	OR	ON	2004/09/07 13:22

S25	2	("6122563").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/09/07 13:38
S26	20	("4958373" "4967381" "5103166" "5105362" "5217834" "5219765" "5226118" "5271796" "5289113" "5294812" "5301143" "5420796" "5440493" "5442561" "5450326" "5467304" "5483175" "5495417" "5511005" "5568408").PN.	USPAT	OR	ON	2004/09/07 13:38
S27	10332	((209/571) or (209/573) or (324/158.1) or (324/759) or (324/764) or (324/765) or (700/96) or (700/108) or (700/109) or (700/121)). CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/09/06 14:44
S28	0	("l5and@pd>2000").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2004/09/07 13:45
S29	10332	((209/571) or (209/573) or (324/158.1) or (324/759) or (324/764) or (324/765) or (700/96) or (700/108) or (700/109) or (700/121)). CCLS.) and @pd > "2000"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/09/07 13:48
S30	10332	((209/571) or (209/573) or (324/158.1) or (324/759) or (324/764) or (324/765) or (700/96) or (700/108) or (700/109) or (700/121)). CCLS.) and (@pd > "2000")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/09/07 13:49
S31	3454	((209/571) or (209/573) or (324/158.1) or (324/759) or (324/764) or (324/765) or (700/96) or (700/108) or (700/109) or (700/121)). CCLS.) and (@py > "2000")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/28 16:21
S32	4	("6788993") or ("5326709"). PN.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/03/28 15:15

S33	33	("4958373" "4967381" "5103166" "5105362" "5217834" "5219765" "5226118" "5271796" "5289113" "5294812" "5301143" "5420796" "5440493" "5442561" "5450326" "5467304" "5483175" "5495417" "5504369" "5511005" "5568408" "5844803" "5856923" "5895962" "5907492" "5915231" "5927512" "6067507" "6122563" "6147316" "6363329" "6529793" "6594611").PN.	US-PGPUB; USPAT; USOCR	OR	ON	2005/03/28 15:15
S34	34	("4510673" "4667403" "4871963" "4954453" "4958373" "4967381" "5003251" "5103166" "5105362" "5217834" "5219765" "5226118" "5271796" "5289113" "5294812" "5301143" "5420796" "5440493" "5442561" "5450326" "5467304" "5483175" "5495417" "5511005" "5516028" "5538141" "5568408" "5581510" "5603412" "5642307" "5844803" "5865319" "5915231" "5927512").PN.	US-PGPUB; USPAT; USOCR	OR	ON	2005/03/28 15:19
S35	177	((semiconductor chip circuit electronic) near3 (sort\$3 separat\$3 process\$3 test\$3)) same (((stor\$3 sav\$3 memory) near3 (test result flag)) and ((identification ID) near3 (code fuse)))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/28 16:21
S36	11053	((209/571) or (209/573) or (324/158.1) or (324/759) or (324/764) or (324/765) or (700/96) or (700/108) or (700/109) or (700/121)). CCLS.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/03/28 16:21
S37	28	((semiconductor chip circuit electronic) near3 (sort\$3 separat\$3 process\$3 test\$3)) same (((stor\$3 sav\$3 memory) near3 (test result flag)) and ((identification ID) near3 (code fuse))).bsum.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/02 12:56
S38	7	S36 and S37	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/03/28 16:27

S39	2	("5895962").PN.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/03/28 16:28
S40	11	("5895962").URPN.	USPAT	OR	ON	2005/03/28 16:30
S41	5	("6130442").URPN.	USPAT	OR	ON	2005/03/28 16:34
S42	16	"6194738"	USPAT	OR	ON	2005/03/28 16:34
S43	4	"5726185"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/02 18:08
S44	10	"5726064"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/02 18:08
S45	9	"5726074"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/02 18:08
S46	61	("4510673" "4667403" "4871963" "4954453" "4958373" "4967381" "5103166" "5105362" "5217834" "5219765" "5226118" "5271796" "5289113" "5294812" "5301143" "5420796" "5440493" "5442561" "5450326" "5467304" "5483175" "5495417" "5511005" "5516028" "5538141" "5568408" "5581510" "5603412" "5642307").PN. OR ("5927512").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2005/09/17 12:03
S47	2	("6130442").PN.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/09/17 12:03
S48	13	("4953277" "5256578" "5550838" "5895962" "5907492").PN. OR ("6130442").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2005/09/17 12:04
S49	9	("5289113" "6115828" "6130442" "6256756" "6330693" "6467054" "6477672" "6622269" "6651202").PN. OR ("6895538").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2005/09/17 12:05

S50	48	("4958373" "4967381" "5103166" "5105362" "5217834" "5219765" "5226118" "5271796" "5289113" "5294812" "5301143" "5420796" "5440493" "5442561" "5450326" "5467304" "5483175" "5495417" "5511005" "5568408").PN. OR ("5907492").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2005/09/17 12:45
S51	71	("3639787" "4020365" "4150331" "4301403" "4465973" "4510673" "4549096" "4595875" "4698589" "4719418" "4743841" "4779043" "4853628" "4942358" "4961053" "4970454" "4992727").PN. OR ("5103166").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2005/09/17 12:46
S52	14	("4488354" "4560583").PN. OR ("4953277").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2005/09/17 14:08
S53	11584	((209/571) or (209/573) or (324/158.1) or (324/759) or (324/764) or (324/765) or (700/96) or (700/108) or (700/109) or (700/121)). CCLS.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/09/10 11:04
S54	12	"5726074"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/04 21:40
S55	32	US-4027246-\$.DID. OR US- 4454413-\$.DID. OR US- 4985988-\$.DID. OR US- 5043657-\$.DID. OR US- 5175774-\$.DID. OR US- 5197650-\$.DID. OR US- 5347463-\$.DID. OR US- 0535071-\$.DID. OR US- 5360747-\$.DID. OR US- 5399531-\$.DID. OR US- 5448488-\$.DID. OR US- 5654204-\$.DID. OR US- 5787012-\$.DID. OR US- 5805472-\$.DID. OR US- 5837558-\$.DID. OR US- 5890807-\$.DID. OR US- 0599491-\$.DID.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/04 21:40
S56	13293	((209/571) or (209/573) or (324/158.1) or (324/759) or (324/764) or (324/765) or (700/96) or (700/108) or (700/109) or (700/121)). CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/08/05 09:50

S57	12	US-5976899-\$.DID. OR US-6265232-\$.DID. OR US-6292009-\$.DID. OR US-6424168-\$.DID. OR US-6534785-\$.DID. OR US-6613590-\$.DID.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/08/05 09:49
S58	19	"5726074"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/02 12:40
S59	13242	((209/571) or (209/573) or (324/158.1) or (324/759) or (324/764) or (324/765) or (700/96) or (700/108) or (700/109) or (700/121)). CCLS.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/04/13 11:21
S60	218	((semiconductor chip circuit electronic) near3 (sort\$3 separat\$3 process\$3 test\$3)) same (((stor\$3 sav\$3 memory) near3 (test result flag)) and ((identification ID) near3 (code fuse)))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/09/10 11:04
S61	43	S59 and S60	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/02/02 12:58
S62	13493	((209/571) or (209/573) or (324/158.1) or (324/759) or (324/764) or (324/765) or (700/96) or (700/108) or (700/109) or (700/121)). CCLS.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/04/13 11:21
S63	219	((semiconductor chip circuit electronic) near3 (sort\$3 separat\$3 process\$3 test\$3)) same (((stor\$3 sav\$3 memory) near3 (test result flag)) and ((identification ID) near3 (code fuse)))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/09/06 14:44
S64	5	("4953277" "5256578" "5550838" "5895962" "5907492").PN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/04/13 11:24
S65	20	("4958373" "4967381" "5103166" "5105362" "5217834" "5219765" "5226118" "5271796" "5289113" "5294812" "5301143" "5420796" "5440493" "5442561" "5450326" "5467304" "5483175" "5495417" "5511005" "5568408").PN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/04/13 11:24

S66	93	((chip circuit electronic) near3 test\$3) same ((stor\$3 sav\$3) and (test result) and (flag data) and (identification near3 code))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/09/06 14:44
S67	225	((semiconductor chip circuit electronic) near3 (sort\$3 separat\$3 process\$3 test\$3)) same (((stor\$3 sav\$3 memory) near3 (test result flag)) and ((identification ID) near3 (code fuse)))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/09/06 14:44
S68	14704	((209/571) or (209/573) or (324/158.1) or (324/759) or (324/764) or (324/765) or (700/96) or (700/108) or (700/109) or (700/121)). CCLS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/09/06 14:46
S69	2	("5726074").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/09/06 14:46
S70	20652	((semiconductor chip circuit electronic) near3 (sort\$3 separat\$3 process\$3 test\$3)) same ((stor\$3 sav\$3 memory) near3 (test result flag))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/09/10 11:05
S71	13999	((209/571) or (209/573) or (324/158.1) or (324/759) or (324/764) or (324/765) or (700/96) or (700/108) or (700/109) or (700/121)). CCLS.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/01/06 14:46
S72	364	((semiconductor chip circuit electronic) near3 (sort\$3 separat\$3 process\$3 test\$3)) same ((stor\$3 sav\$3 memory) near3 (test result flag) and ((fabricat\$3 manufactur\$3 produc\$3 process\$3) near2 (error mistake flaw deviat \$4)))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/01/05 21:37
S73	0	((semiconductor chip circuit electronic) near3 (sort\$3 separat\$3 process\$3 test\$3)) same ((stor\$3 sav\$3 memory) near3 (test result flag) and ((fabricat\$3 manufactur\$3 produc\$3 process\$3) near2 (error mistake flaw deviat \$4))).clms.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/09/10 11:10
S74	30	S71 and S72	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/09/10 11:10

S75	18	("4878179" "5206582" "5298433" "5355320" "5390129" "5475618" "5511005" "5557559" "5598341").PN. OR ("5822717").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/09/10 11:17
S76	47	("3751647" "4849804" "5450326" "5475695").PN. OR ("5598341").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/09/10 11:21
S77	47	("3751647" "4849804" "5450326" "5475695").PN. OR ("5598341").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/09/10 11:21
S78	12	"5550838"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/09/10 12:21
S79	14	("4363407" "4651088" "4727318" "5053698" "5062109").PN. OR ("5550838").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/09/10 12:34
S80	47	("4622647" "4869813" "4878179" "4901218" "5086397" "5097421" "5111404" "5150288").PN. OR ("5355320").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/09/10 12:47
S81	14349	((209/571) or (209/573) or (324/158.1) or (324/759) or (324/764) or (324/765) or (700/96) or (700/108) or (700/109) or (700/121)). CCLS.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/01/05 21:36
S82	376	((semiconductor chip circuit electronic) near3 (sort\$3 separat\$3 process\$3 test\$3)) same ((stor\$3 sav\$3 memory) near3 (test result flag) and ((fabricat\$3 manufactur\$3 produc\$3 process\$3) near2 (error mistake flaw deviat \$4)))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/01/05 21:37
S83	38	((semiconductor chip circuit electronic) near3 (sort\$3 separat\$3 process\$3 test\$3)) same ((stor\$3 sav\$3 memory) near3 (test result flag) and ((fabricat\$3 manufactur\$3 produc\$3 process\$3) near2 (error mistake flaw deviat \$4))).clm.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/01/05 22:36
S84	4	("7120513" "7155300").PN.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/01/05 21:39

S85	143	("20040024551" "4027246" "4032949" "4150331" "4454413" "4455495" "4510673" "4534014" "4667403" "4871963" "4954453" "4958373" "4967381" "4985988" "5003251" "5043657" "5103166" "5105362" "5110754" "5118369" "5175774" "5197650" "5217834" "5219765" "5226118" "5235550" "5253208" "5256562" "5256578" "5271796" "5289113" "5294812" "5296402" "5301143" "5326709" "5345110" "5347463" "5350715" "5352945" "5355320" "5360747" "5399531" "5420796" "5424652" "5428311" "5440240" "5440493" "5442561" "5448488" "5450326" "5467304" "5477493" "5483175" "5495417" "5504369" "5511005" "5516028" "5537325" "5538141" "5539235" "5563832" "5568408" "5570293" "5581510" "5590069" "5600171" "5603412" "5606193" "5617366" "5619469" "5625816" "5642307" "5654204" "5726074" "5764650" "5787012" "5787190" "5801067" "5801965" "5805472" "5828778" "5837558" "5844803" "5856923" "5865319" "5867505" "5889674" "5890807" "5895962" "5907492" "5915231" "5927512" "5963881" "5976899" "5991699" "5994915" "6000830" "6018686" "6049624" "6055463" "6067507" "6072574" "6075216" "6100486" "6122563" "6130442" "6138256" "6147316" "6148307" "6190972" "6194738" "6208947" "6219810" "6226394" "6259520" "6265232" "6292009" "6307171" "6350959" "6363295" "6363329" "6365421" "6365860" "6365861") .PN.	US-PGPUB; USPAT; USOCR	OR	ON	2008/01/05 22:03
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S86	2	("5726074").PN.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/01/05 22:26
S87	87	("4027246" "4150331" "4166574" "4419747").PN. OR ("4510673").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2008/01/05 22:34
S88	1295	((semiconductor chip circuit electronic) near3 (sort\$3 separat\$3 process\$3 test\$3)) same ((stor\$3 sav\$3 memory) near3 (test result flag) and (different near2 test\$3))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/01/05 22:38
S89	104	((semiconductor chip circuit electronic) near3 (sort\$3 separat\$3 process\$3 test\$3)) same ((stor\$3 sav\$3 memory) near3 (test result flag) and (different near3 (test\$3 and level)))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/01/05 23:09
S90	5	S89 and (failure near2 analysis)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/01/05 22:46
S91	1	((semiconductor chip circuit electronic) near3 (sort\$3 separat\$3 process\$3 test\$3)) same ((stor\$3 sav\$3 memory) near3 (test result flag) and (different near3 (test\$3 and reliability)))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/01/06 14:44
S92	9656	((semiconductor chip circuit electronic) near3 (sort\$3 separat\$3 process\$3 test\$3)) same ((test result flag) and reliability)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/01/06 14:45
S93	2417	((semiconductor chip circuit electronic) near3 (sort\$3 separat\$3 process\$3 test\$3)) same ((test result flag) near3 reliability)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/01/06 14:47

S94	14349	((209/571) or (209/573) or (324/158.1) or (324/759) or (324/764) or (324/765) or (700/96) or (700/108) or (700/109) or (700/121)). CCLS.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/01/06 14:46
S95	251	S93 and S94	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/01/06 14:46
S96	519	((semiconductor chip circuit electronic) near3 (sort\$3 separat\$3 process\$3 test\$3)) same (different and (test result flag) near3 reliability)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/01/06 14:47
S97	96	S94 and S96	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/01/06 14:47
S98	14814	((209/571) or (209/573) or (324/158.1) or (324/759) or (324/764) or (324/765) or (700/96) or (700/108) or (700/109) or (700/121)). CCLS.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/06/11 11:13
S99	4	((("5946497") or ("5950012")). PN.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/06/11 11:14
S100	562	((semiconductor chip circuit electronic) near3 (sort\$3 separat\$3 process\$3 test\$3)) same (different and (test result flag) near3 reliability)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/06/11 11:14
S101	108	S98 and S100	US-PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/06/11 11:15
S102	5	"092185".ap.	US-PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/06/11 21:58
S103	10	((("5946497") or ("5950012") or ("5301143") or ("5294812") or ("5103166")). PN.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2008/06/11 22:12
S104	79	("4896204" "4908690" "5065222" "5089866" "5105235" "5177567").PN. OR ("5294812").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2008/06/11 22:33

S105	147	("20040024551" "4027246" "4032949" "4150331" "4454413" "4455495" "4510673" "4534014" "4667403" "4871963" "4954453" "4958373" "4967381" "4985988" "5003251" "5043657" "5103166" "5105362" "5110754" "5118369" "5150331" "5175774" "5197650" "5217834" "5219765" "5226118" "5235550" "5253208" "5256562" "5256578" "5271796" "5289113" "5294812" "5296402" "5301143" "5326709" "5345110" "5347463" "5350715" "5352945" "5355320" "5360747" "5399531" "5420796" "5424652" "5428311" "5440240" "5440493" "5442561" "5448488" "5450326" "5467304" "5477493" "5483175" "5495417" "5504369" "5511005" "5516028" "5537325" "5538141" "5539235" "5550838" "5563832" "5568408" "5570293" "5581510" "5590069" "5600171" "5603412" "5606193" "5617366" "5619469" "5625816" "5642307" "5654204" "5726074" "5764650" "5787012" "5787190" "5801067" "5801965" "5805472" "5822218" "5828778" "5837558" "5844803" "5856923" "5865319" "5867505" "5889674" "5890807" "5895962" "5907492" "5915231" "5927512" "5963881" "5976899" "5991699" "5994915" "6000830" "6018686" "6049624" "6055463" "6067507" "6072574" "6075216" "6100486" "6122563" "6130442" "6138256" "6147316" "6148307" "6190972" "6194738" "6208947" "6219810" "6226394" "6259520" "6265232" "6292009" "6307171" "6350959" "6363295" "6363329").PN.	US-PGPUB; USPAT; USOCR	OR	ON	2008/06/11 22:34
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